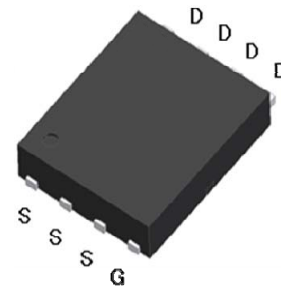
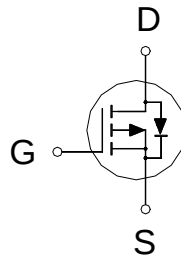


P-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

BV_{DSS}	-30V
$R_{DS(on)} (MAX.)$	3.1m Ω
I_D	-85A



UIS, Rg 100% Tested

Pb-Free Lead Plating & Halogen Free



ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	I_D	-85	A
	$T_C = 100^\circ\text{C}$		-65	
Pulsed Drain Current ¹		I_{DM}	-260	
Avalanche Current		I_{AS}	-80	
Avalanche Energy	$L = 0.1\text{mH}$, $I_D = -80\text{A}$, $R_G = 25\Omega$	E_{AS}	320	mJ
Repetitive Avalanche Energy ²	$L = 0.05\text{mH}$	E_{AR}	160	
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	69	W
	$T_C = 100^\circ\text{C}$		27	
Operating Junction & Storage Temperature Range		$T_{j, T_{stg}}$	-55 to 150	$^\circ\text{C}$

100% UIS testing in condition of $V_D = -15\text{V}$, $L = 0.1\text{mH}$, $V_G = -10\text{V}$, $I_L = -50\text{A}$, Rated $V_{DS} = -30\text{V}$ P-CH

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	$R_{\theta JC}$		1.8	$^\circ\text{C} / \text{W}$
Junction-to-Ambient ³	$R_{\theta JA}$		62.5	

¹Pulse width limited by maximum junction temperature.

²Duty cycle $\leq 1\%$

ELECTRICAL CHARACTERISTICS (T_J = 25 °C, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0V, I _D = -250μA	-30			V
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = -250μA	-1	-1.5	-3	
Gate-Body Leakage	I _{GSS}	V _{DS} = 0V, V _{GS} = ±20V			±100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = -24V, V _{GS} = 0V			-1	μA
		V _{DS} = -20V, V _{GS} = 0V, T _J = 125 °C			-10	
On-State Drain Current ¹	I _{D(ON)}	V _{DS} = -5V, V _{GS} = -10V	-85			A
Drain-Source On-State Resistance ¹	R _{DS(ON)}	V _{GS} = -10V, I _D = -30A		2.7	3.1	mΩ
		V _{GS} = -4.5V, I _D = -30A		4.0	5.0	
Forward Transconductance ¹	g _{fs}	V _{DS} = -5V, I _D = -30A		70		S
DYNAMIC						
Input Capacitance	C _{iss}	V _{GS} = 0V, V _{DS} = -15V, f = 1MHz		6400		pF
Output Capacitance	C _{oss}			913		
Reverse Transfer Capacitance	C _{rss}			656		
Gate Resistance	R _g	V _{GS} = 15mV, V _{DS} = 0V, f = 1MHz		3.4		Ω
Total Gate Charge ^{1,2}	Q _g	V _{DS} = -15V, V _{GS} = -10V, I _D = -30A		96.5		nC
Gate-Source Charge ^{1,2}	Q _{gs}			24.8		
Gate-Drain Charge ^{1,2}	Q _{gd}			13.8		
Turn-On Delay Time ^{1,2}	t _{d(on)}	V _{DS} = -15V, I _D = -1A, V _{GS} = -10V, R _{GS} = 2.7Ω		15		nS
Rise Time ^{1,2}	t _r			20		
Turn-Off Delay Time ^{1,2}	t _{d(off)}			130		
Fall Time ^{1,2}	t _f			55		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T _c = 25 °C)						
Continuous Current	I _S				-85	A
Pulsed Current ³	I _{SM}				-260	
Forward Voltage ¹	V _{SD}	I _F = -30A, V _{GS} = 0V			-1.2	V
Reverse Recovery Time	t _{rr}	I _F = I _S , dI _F /dt = 100A / μS		26		nS
Reverse Recovery Charge	Q _{rr}			80		nC

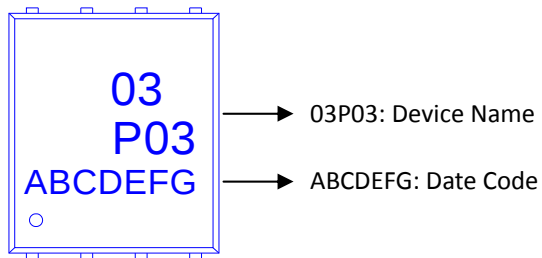
¹Pulse test : Pulse Width $\leq 300\mu$ sec, Duty Cycle $\leq 2\%$.

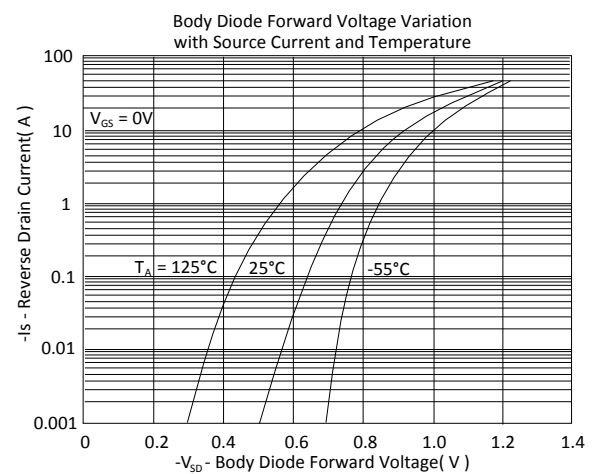
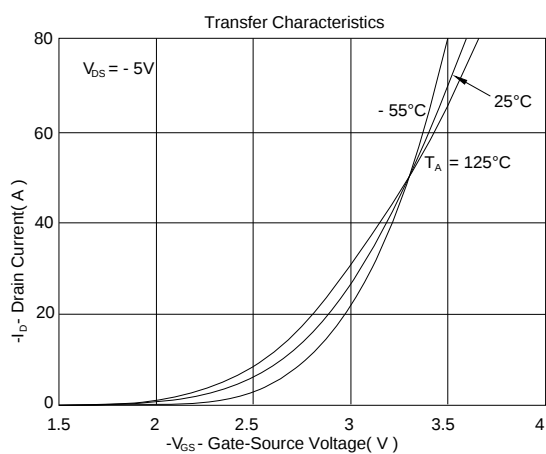
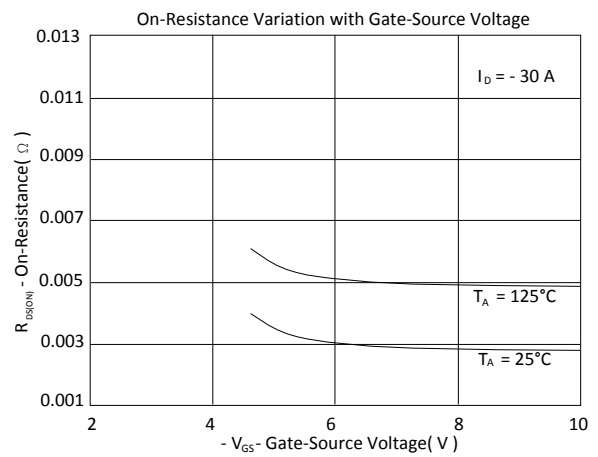
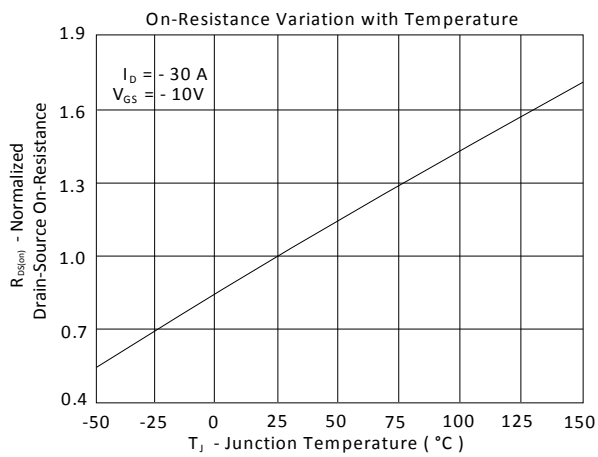
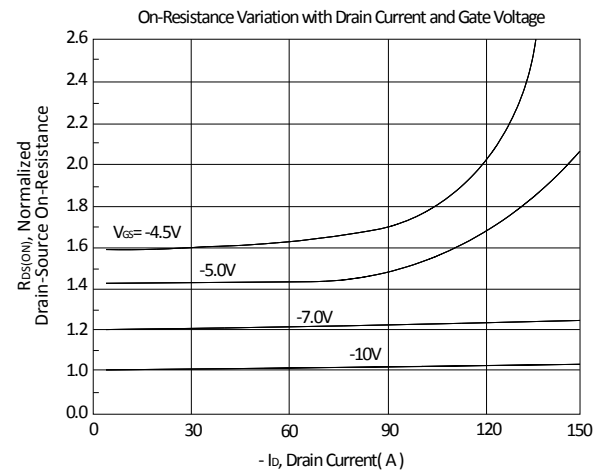
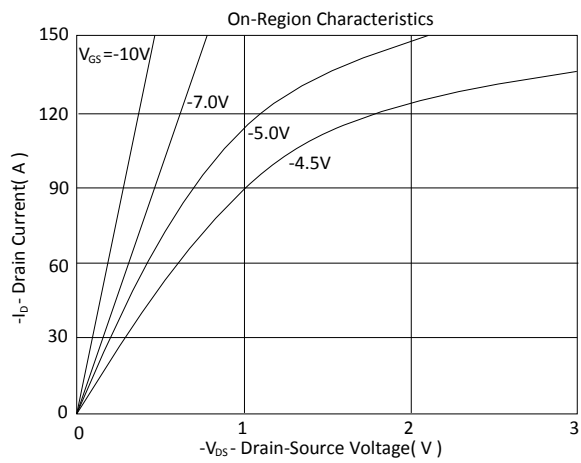
²Independent of operating temperature.

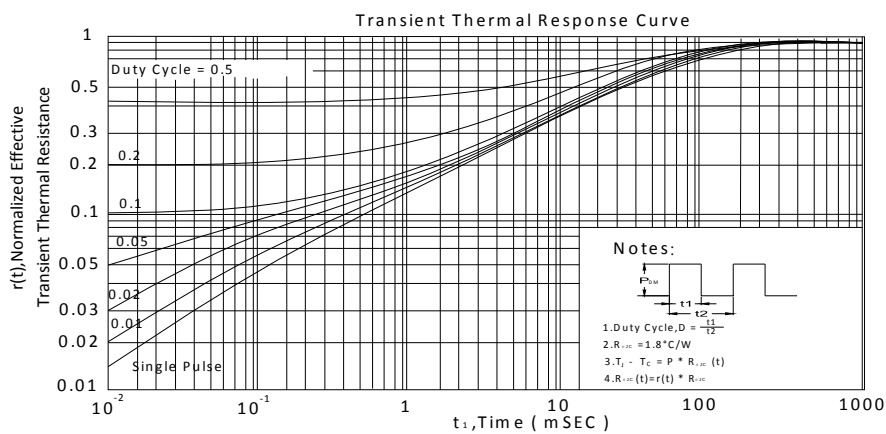
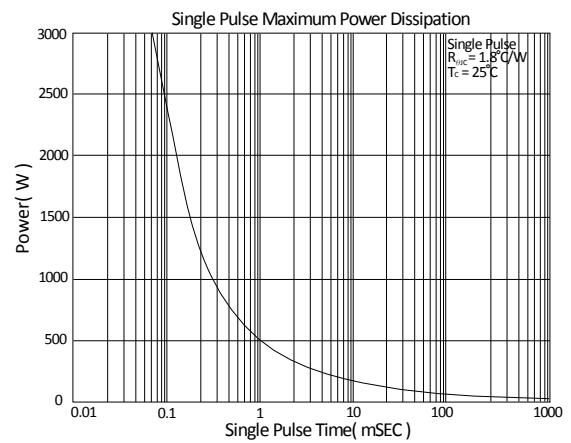
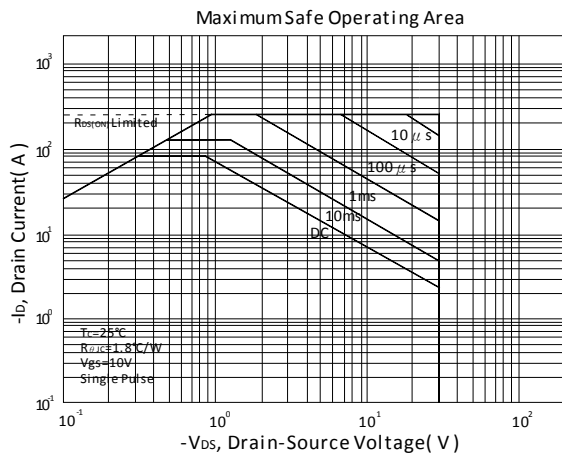
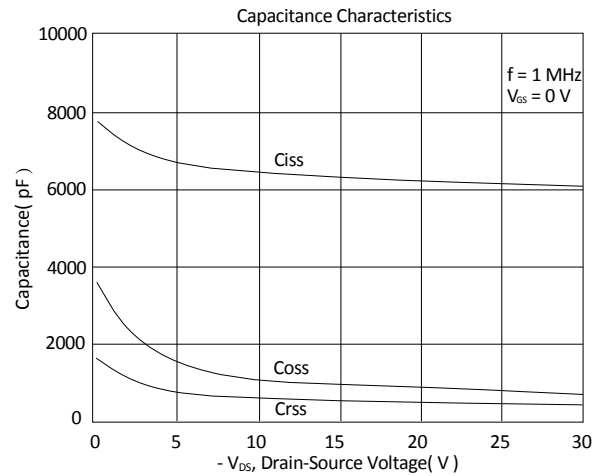
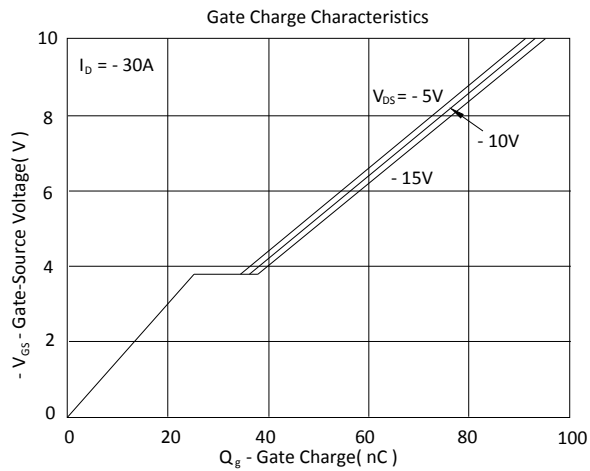
³Pulse width limited by maximum junction

temperature. **Ordering & Marking Information:**

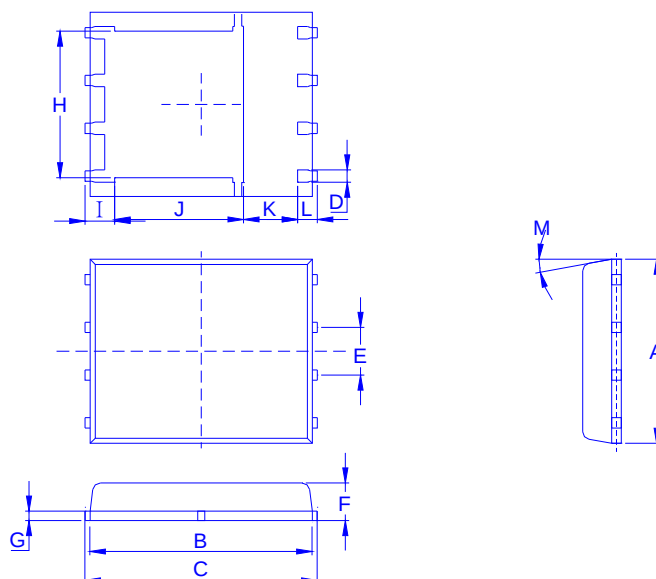
Device Name: LB03P03C for EDFN 5 x 6







Outline Drawing



Dimension in mm

Dimension	A	B	C	D	E	F	G	H	I	J	K	L	M
Min.	4.80	5.50	5.90	0.3		0.85	0.15	3.67	0.41	3.00	0.94	0.45	0°
Typ.					1.27								
Max.	5.30	5.90	6.15	0.51		1.20	0.30	4.54	0.85	3.92	1.7	0.71	12°

Recommended minimum pads

